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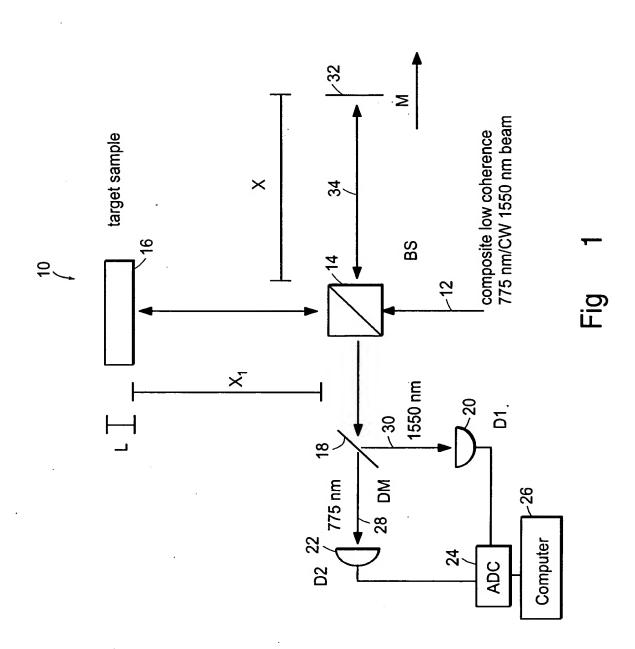
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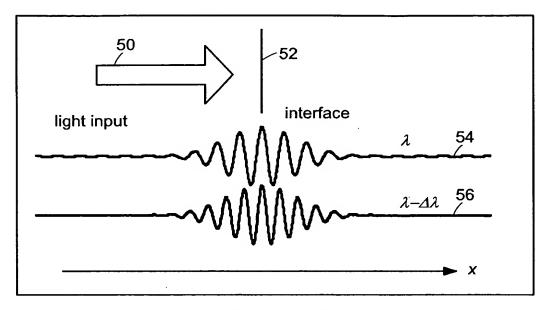
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Inventors: Christopher M. Fang-Yen et al.
Title: Systems and Methods for Phase Measurements



Fig

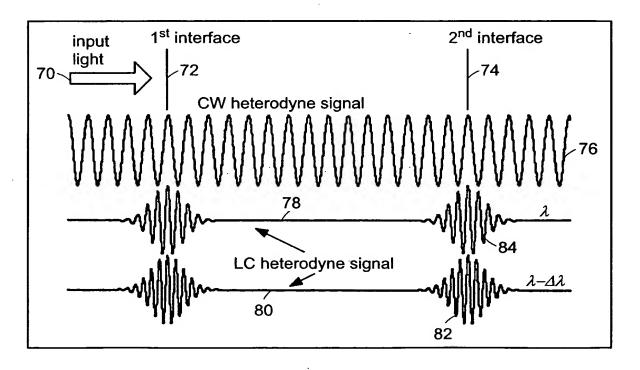
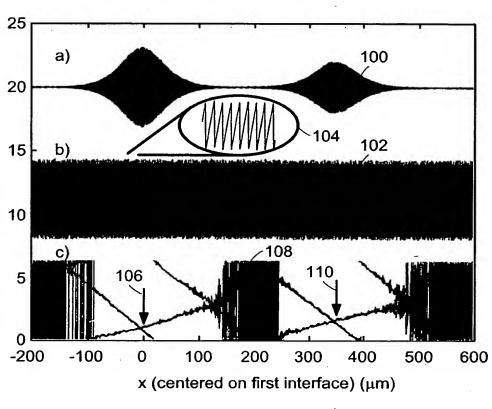
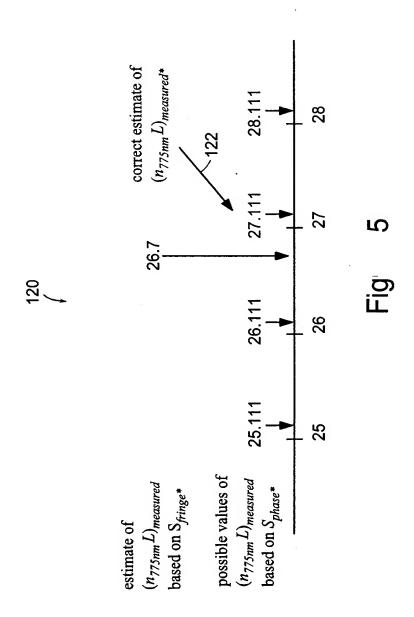


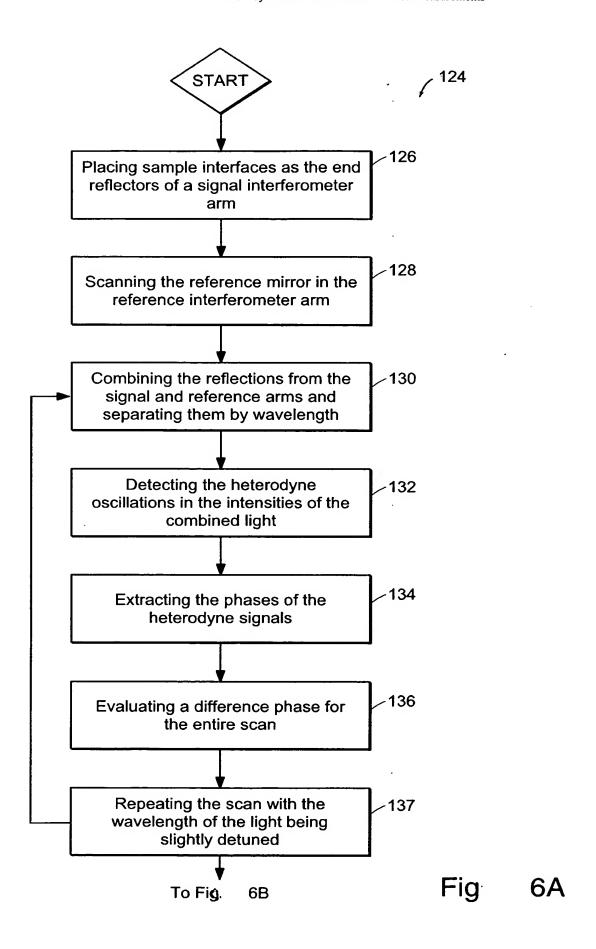
Fig 3



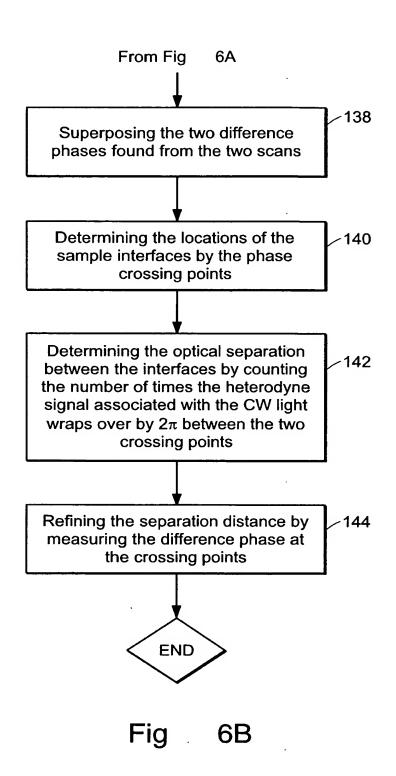
Fig

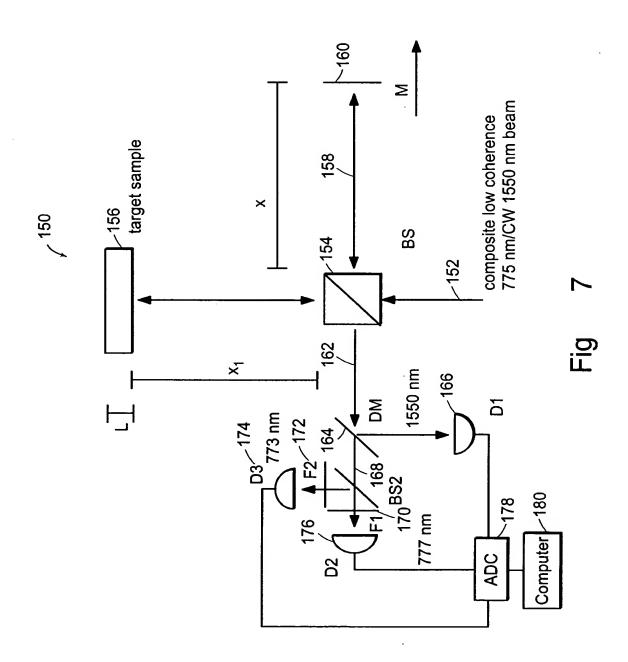


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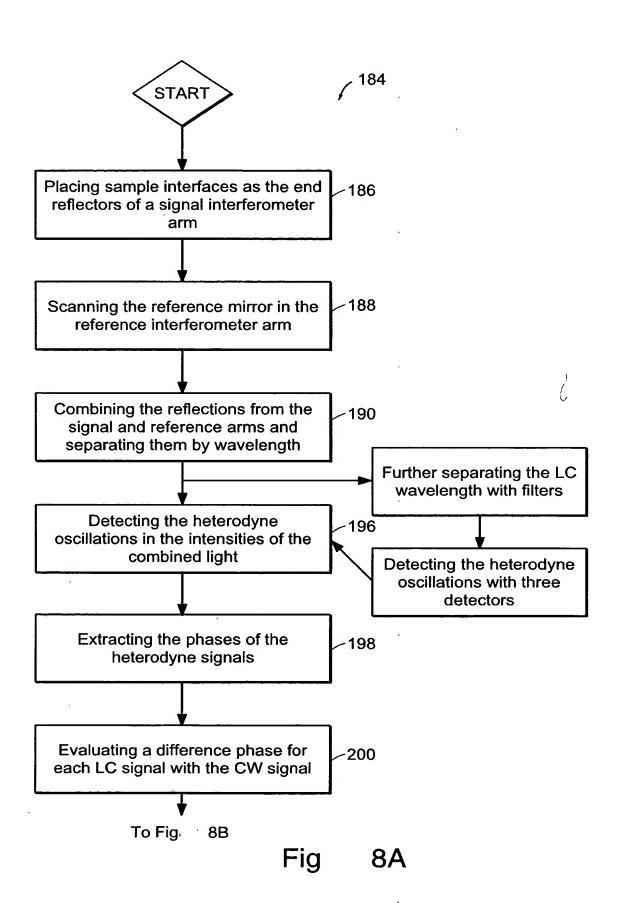


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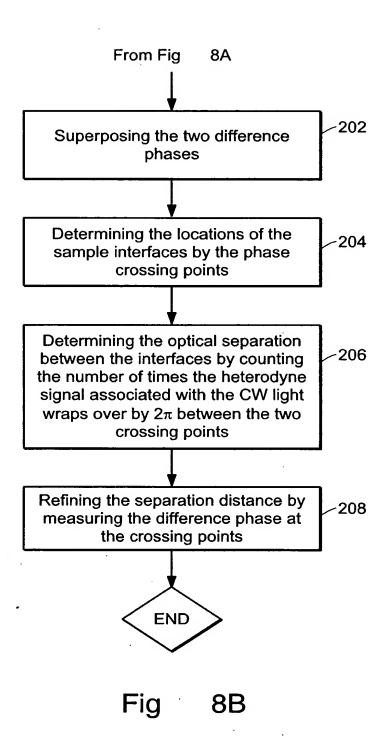


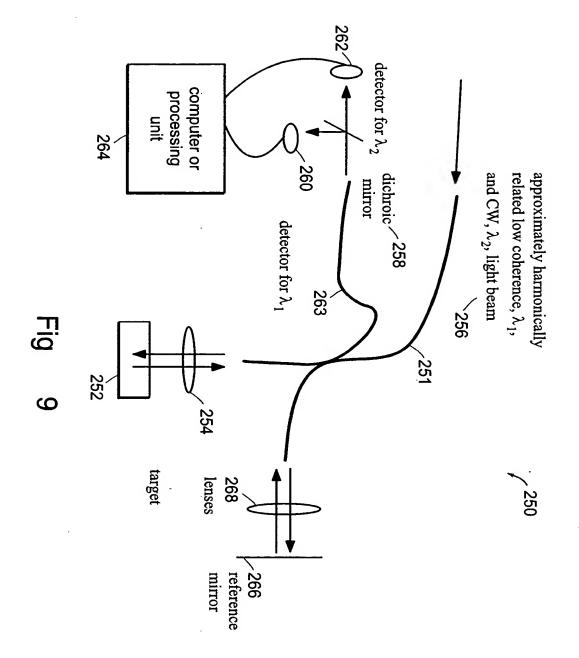


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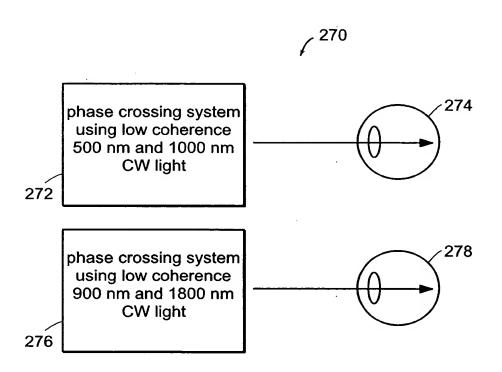
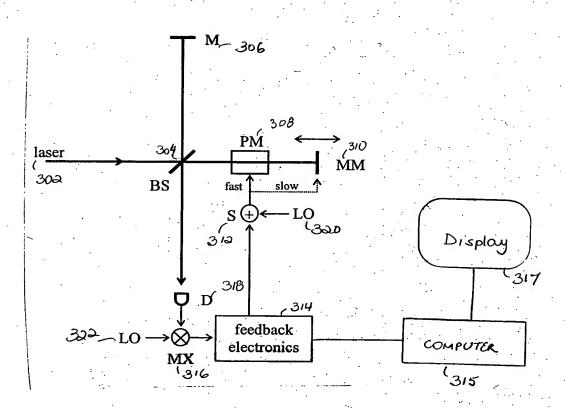


Fig 10

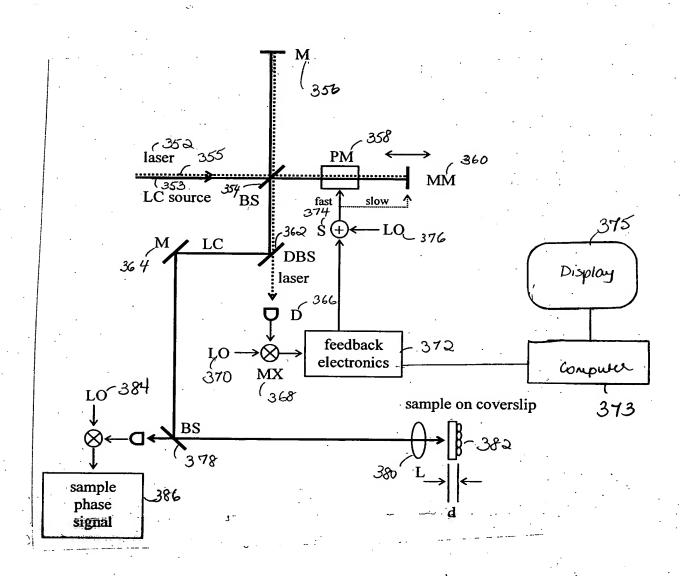




Docket No.: 301505.3002-103
Inventors: Christopher M. Fang-Yen et al.

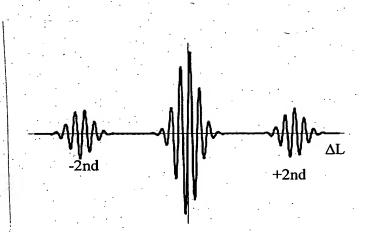
Title: Systems and Methods for Phase Measurements

3350

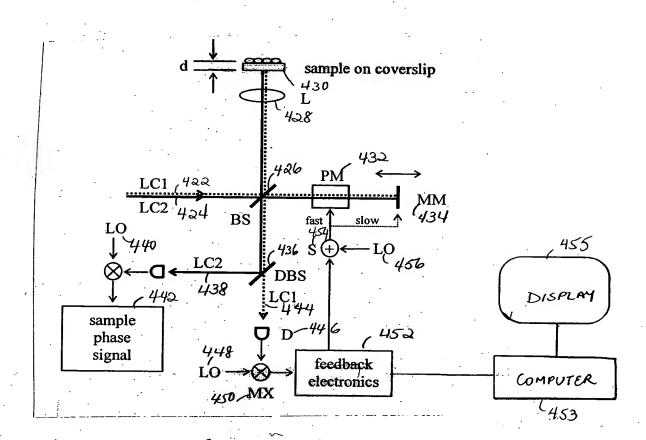


12

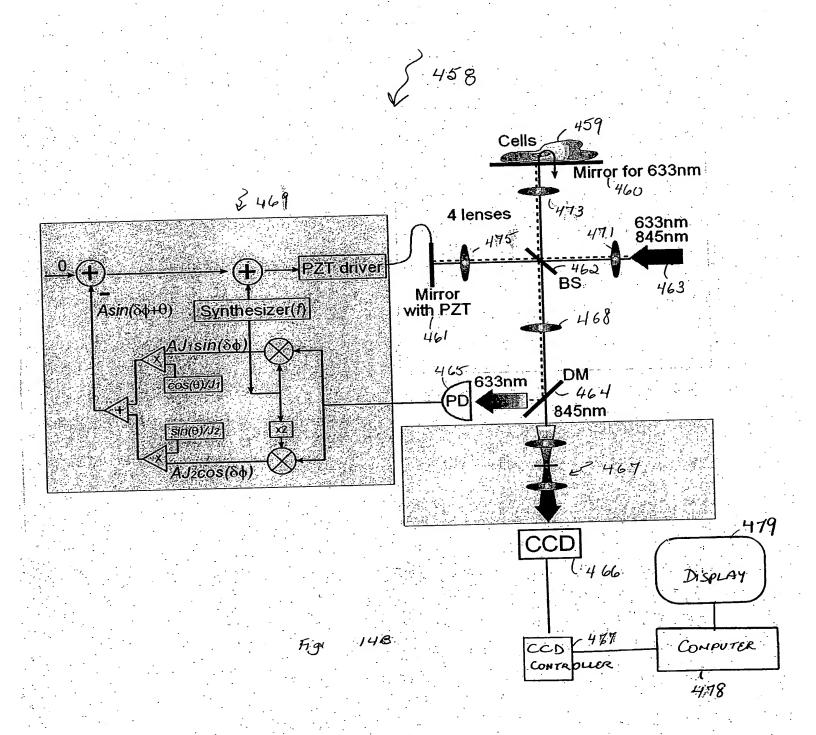




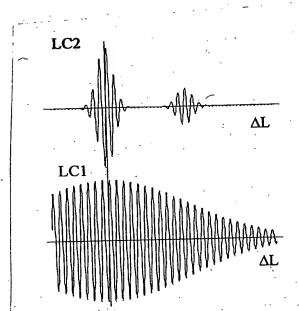




14A

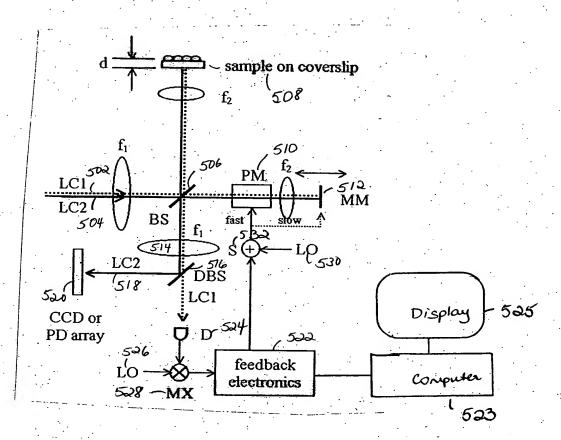




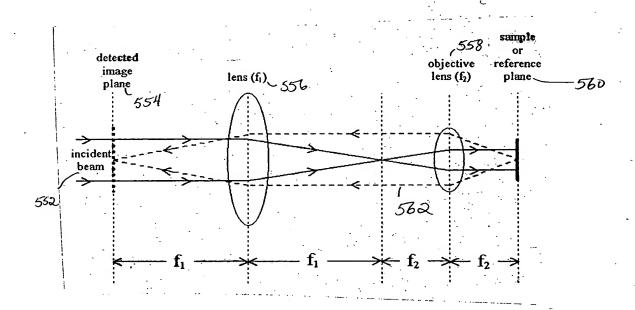


15A

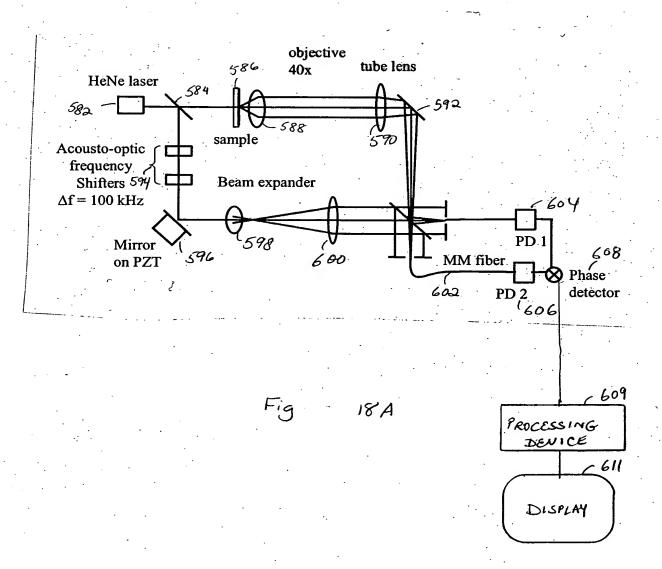




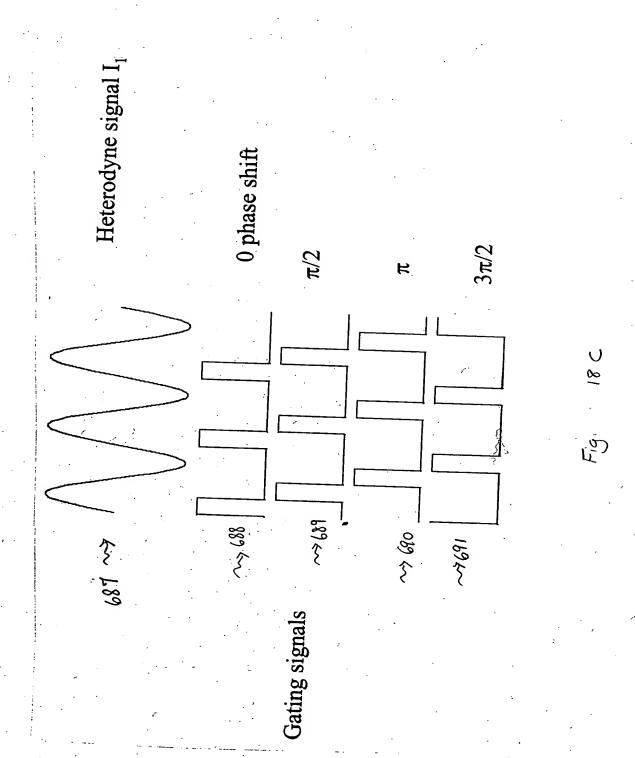
3 550







5,670





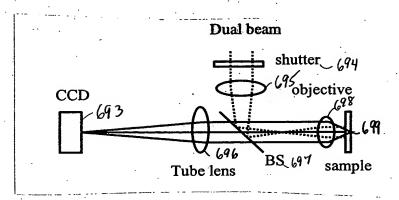


Fig. 460 18D

Inventors: Christopher M. Fang-Yen et al.



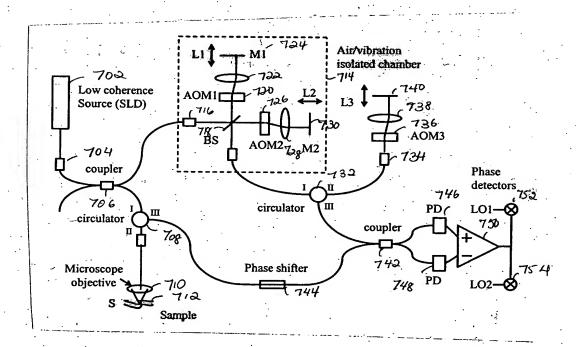
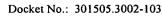
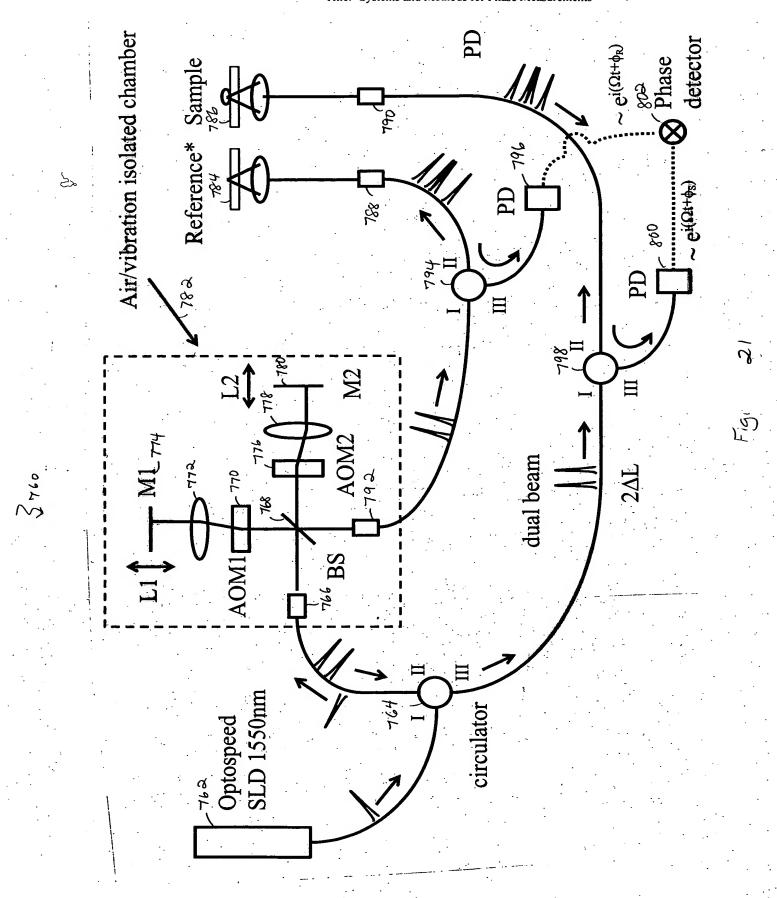
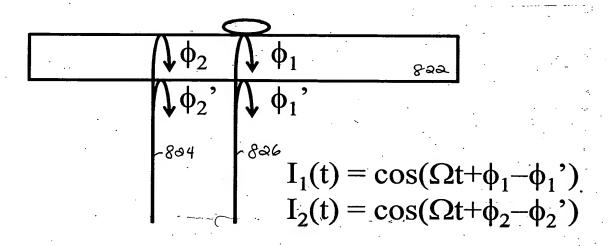
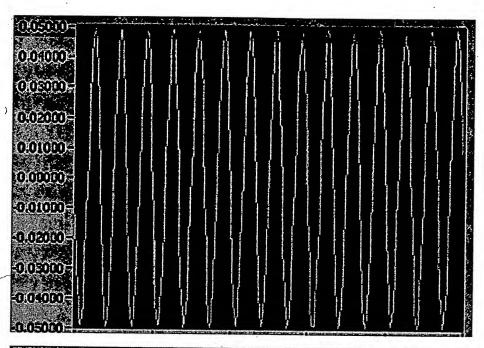


Fig. 20



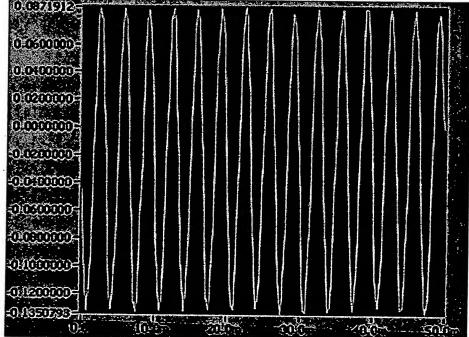




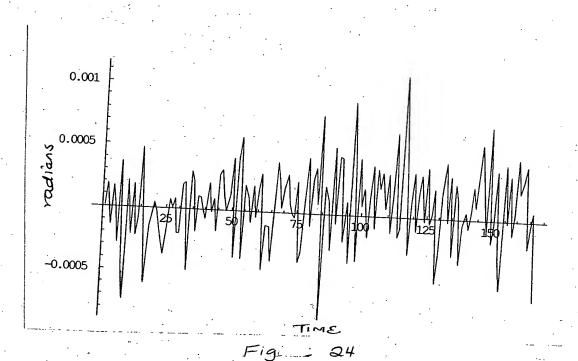


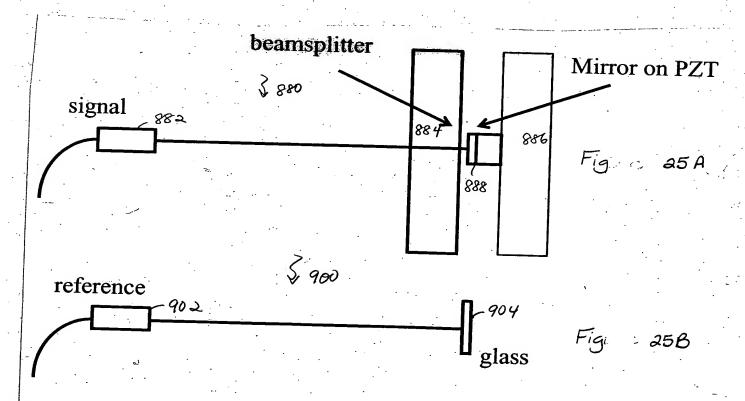
PZT Voltage

850 >> Phase change (1550nm)

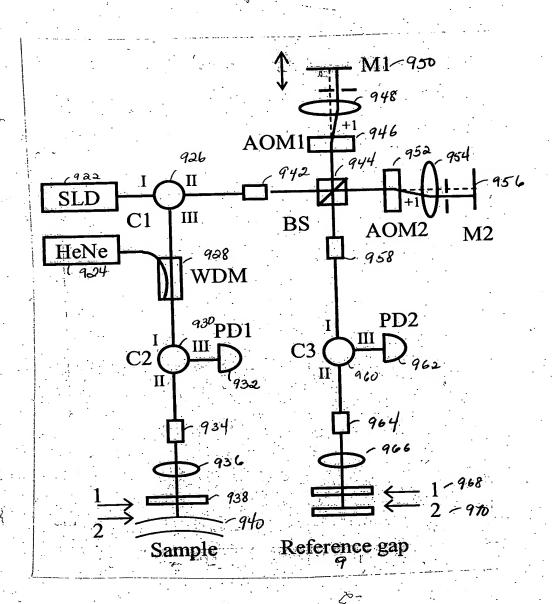




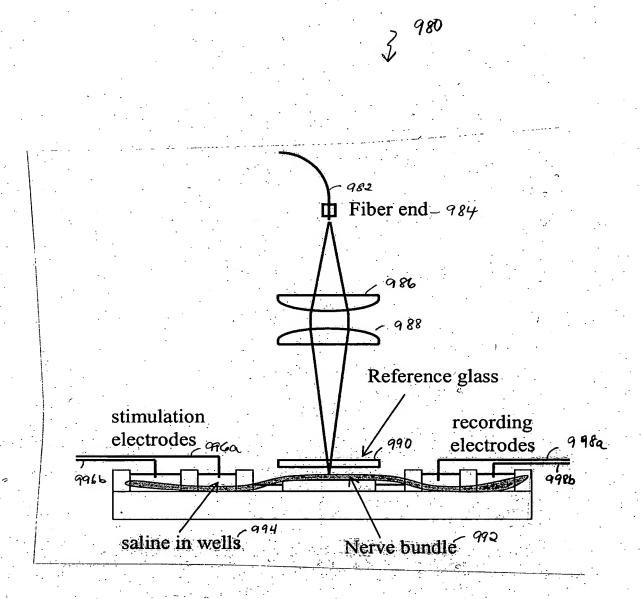




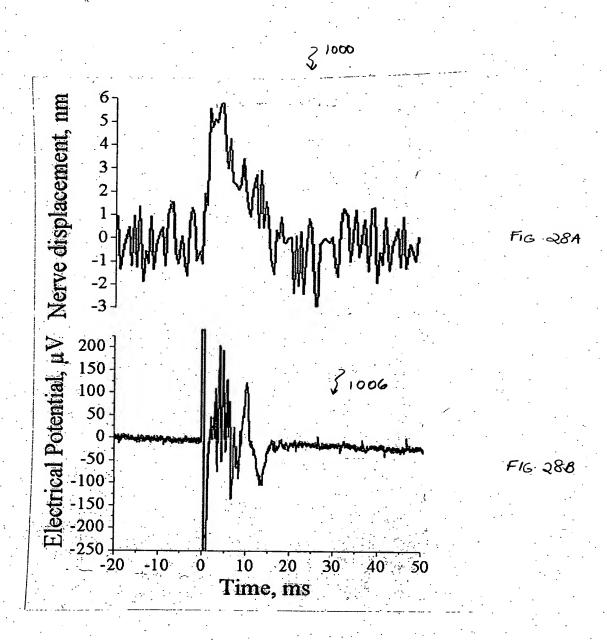




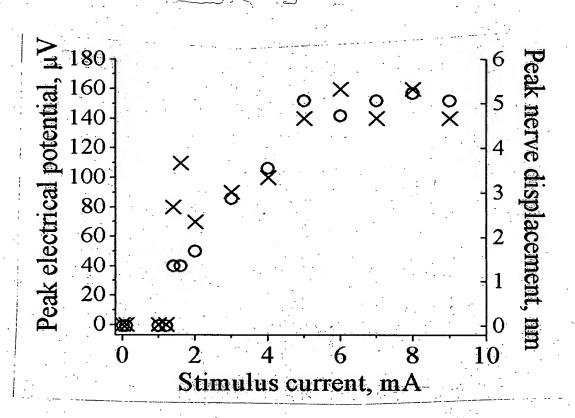
F16.26



F16.27







F16.29

Inventors: Christopher M. Fang-Yen et al.

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3 1000

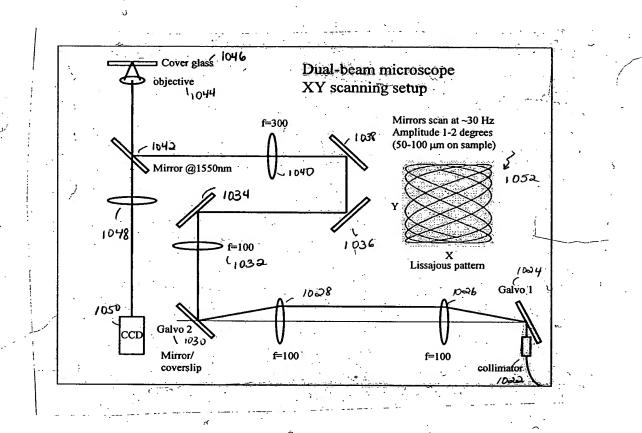


FIG. 30.

1070

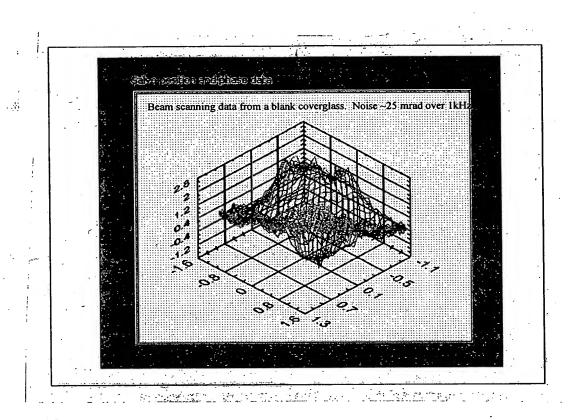


FIG. 31

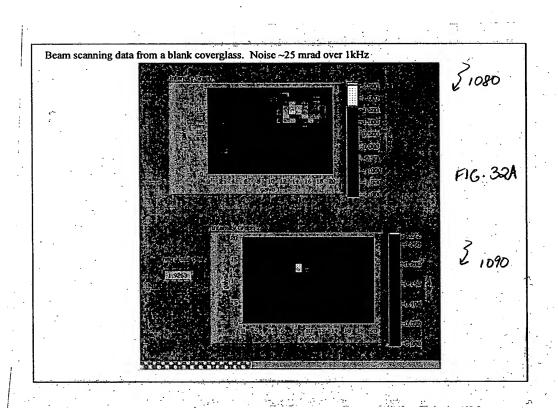


FIG. 32B



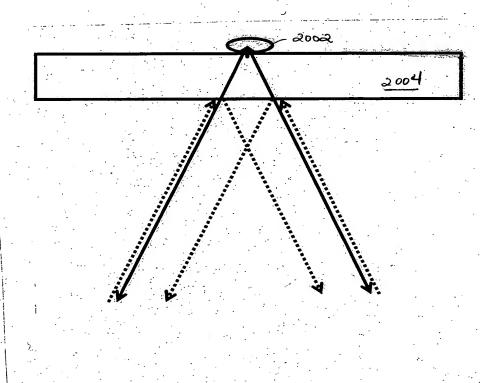
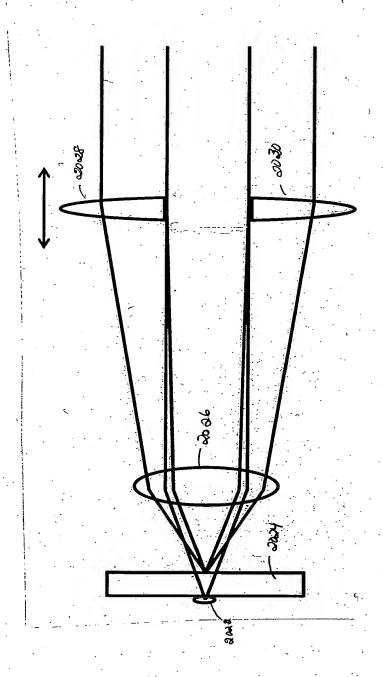
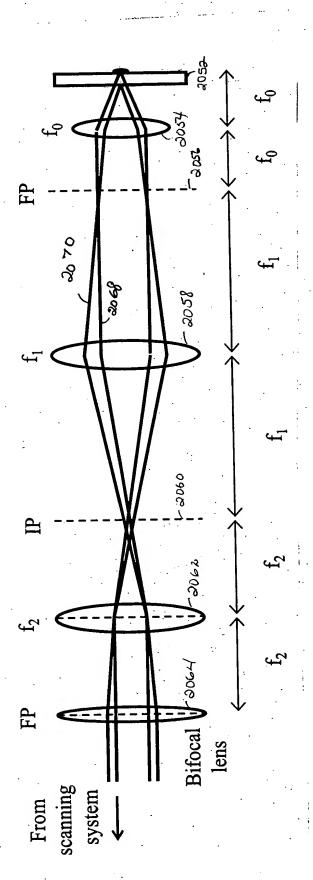


FIG. 33





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Inventors: Christopher M. Fang-Yen et al.

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5 2080

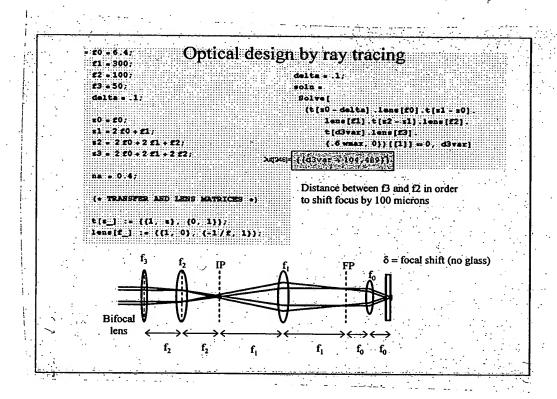
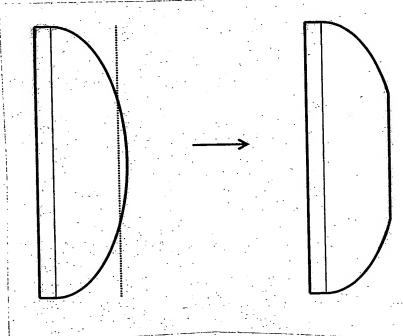


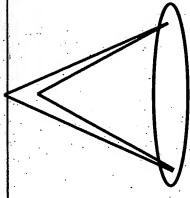
FIG. 36



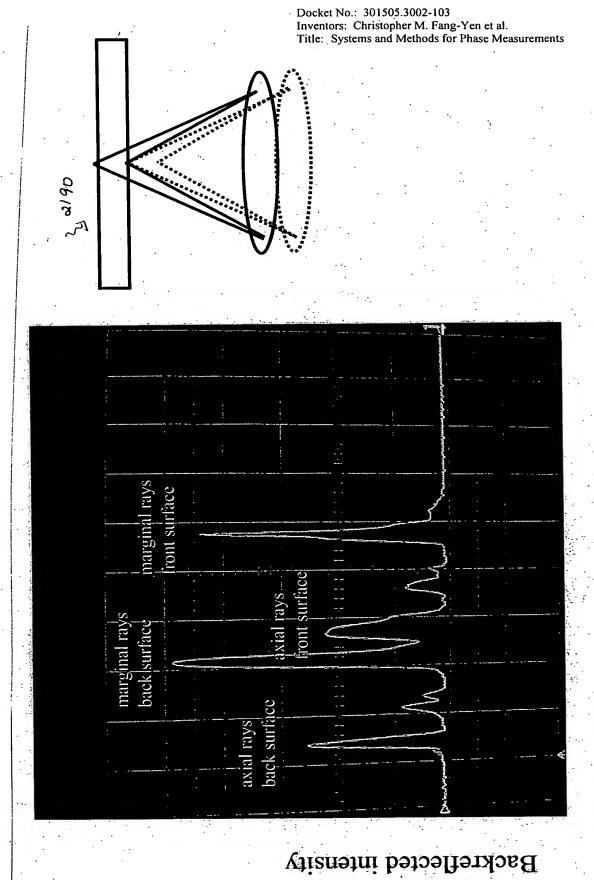


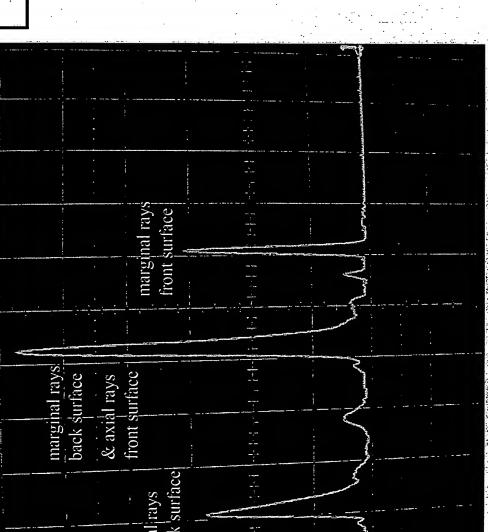
Objective focus position

Backreflected intensity (max=5%)



Backreflected intensity

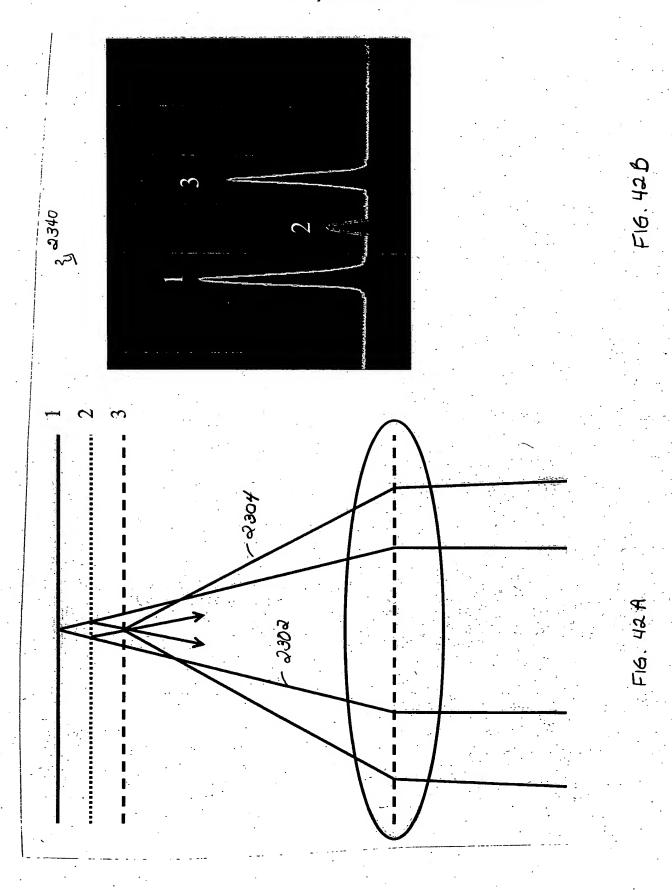


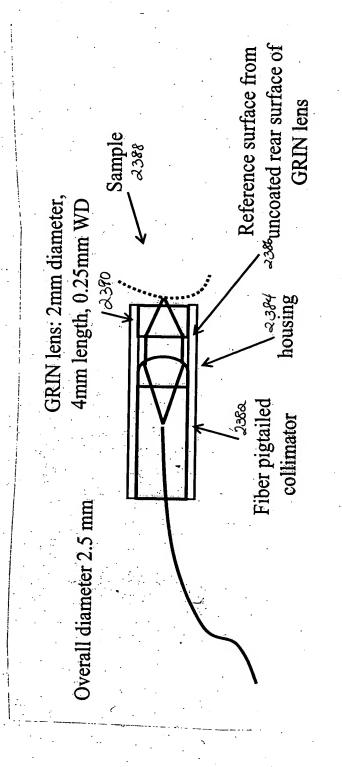


Backreflected intensity

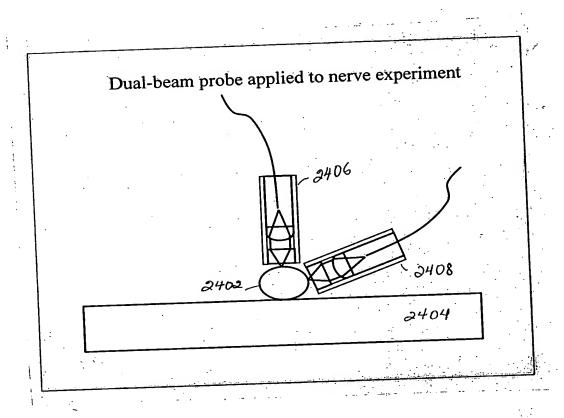
2240

14 4





3 2400



F16. 44



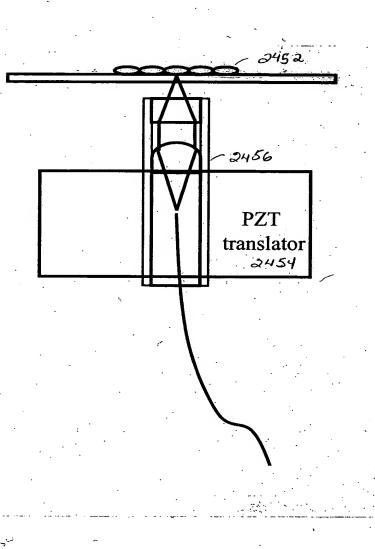
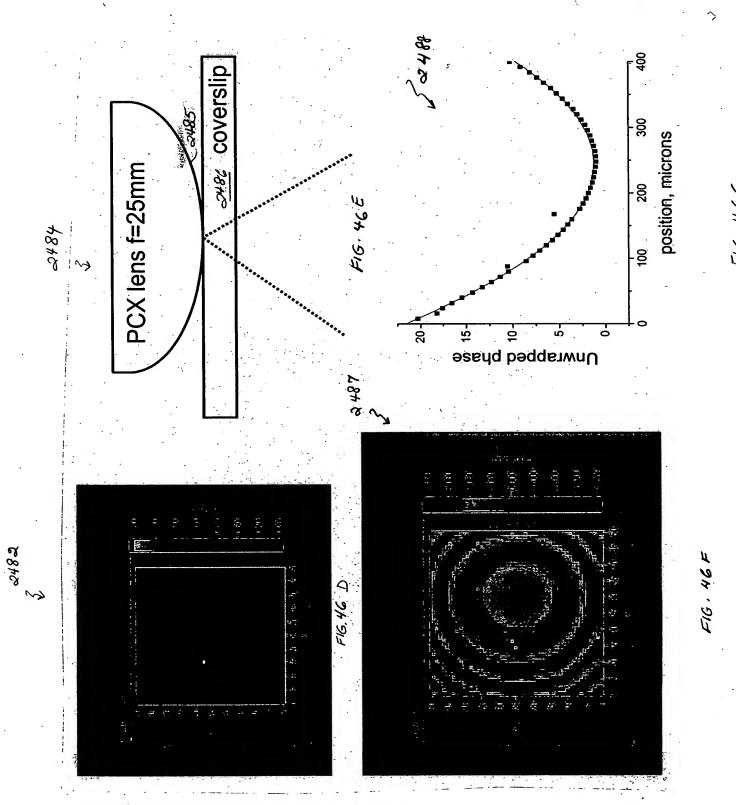
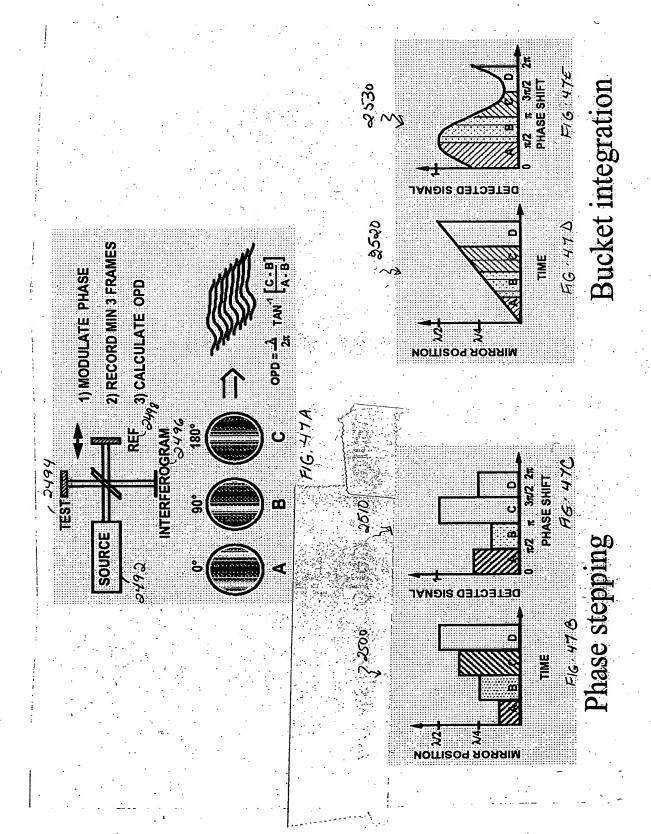
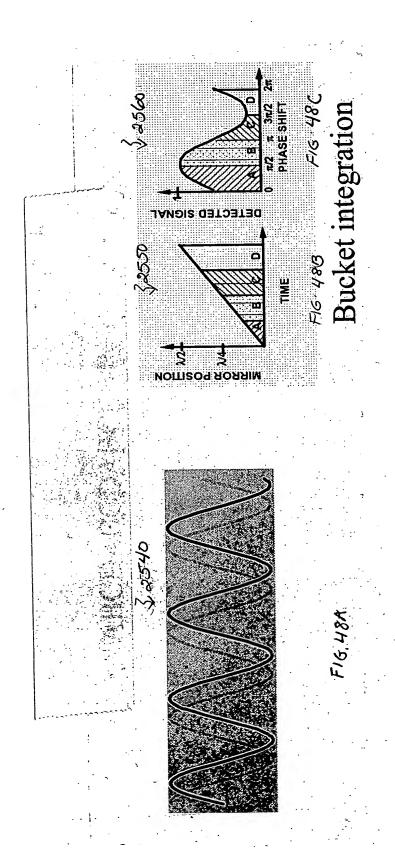


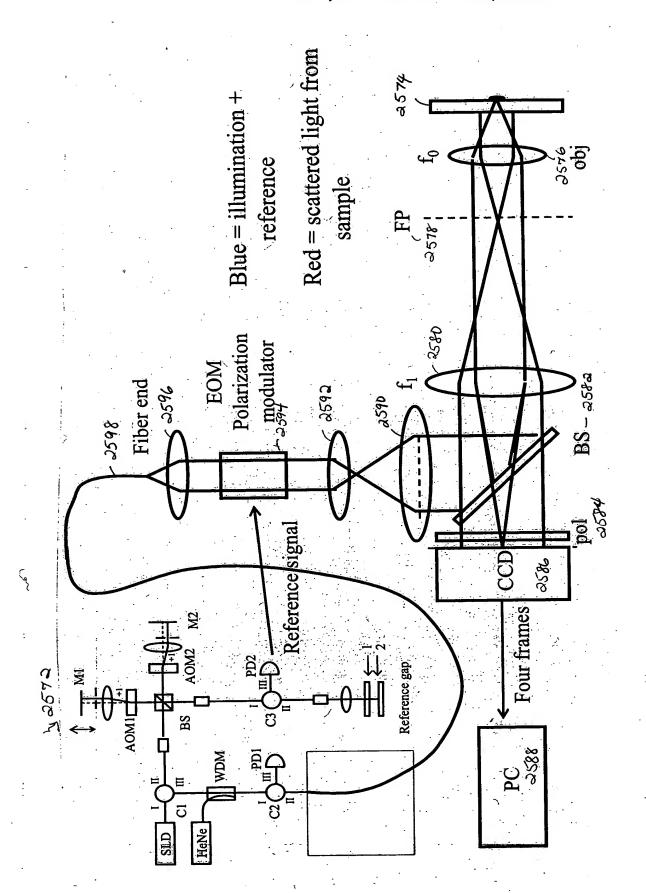
FIG. 45

0.0

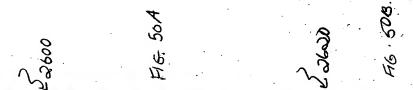


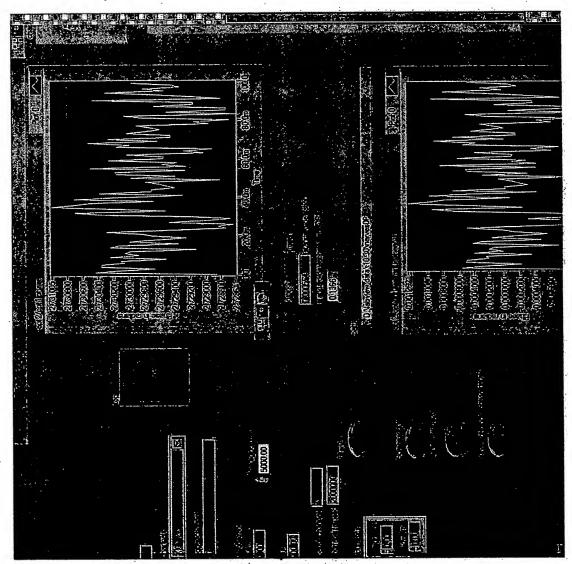


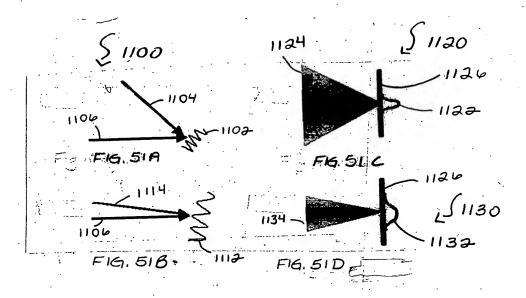


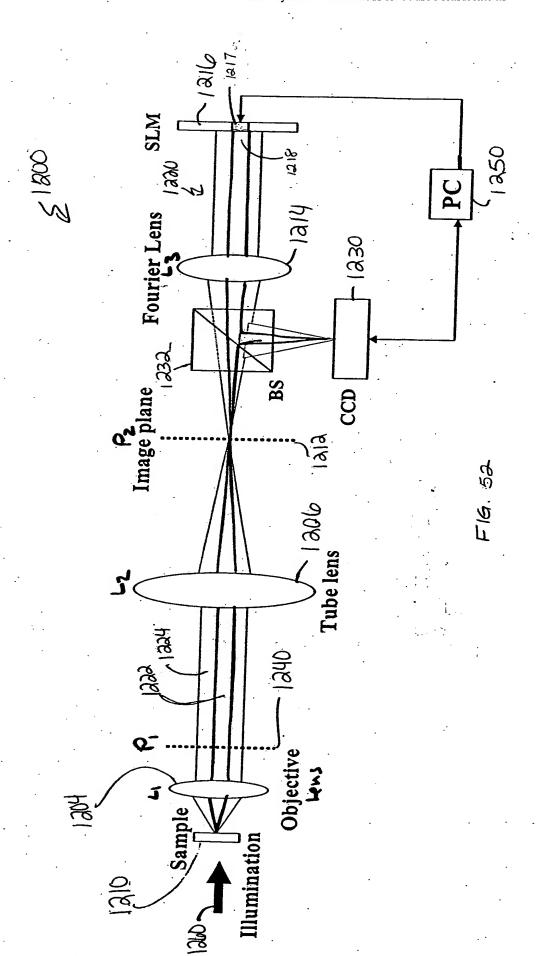


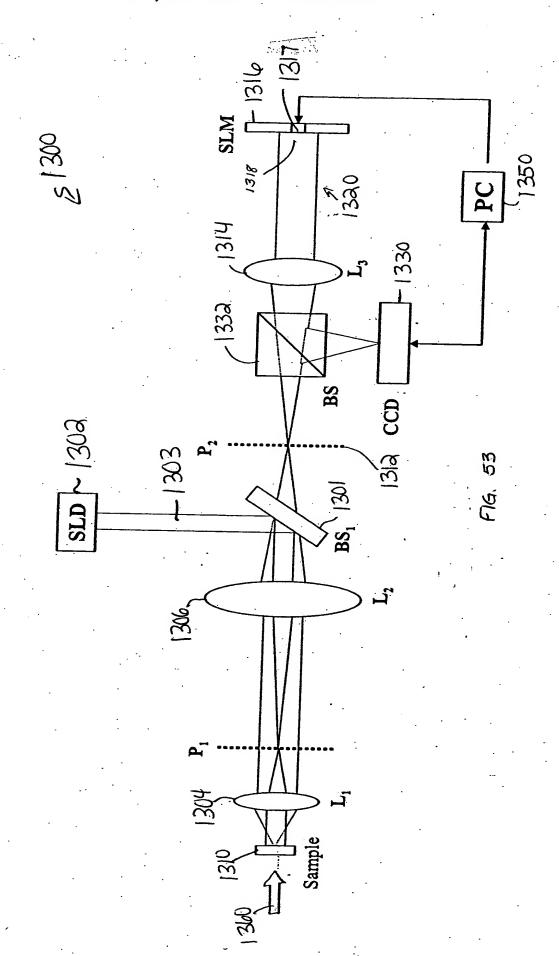
\$ 2570











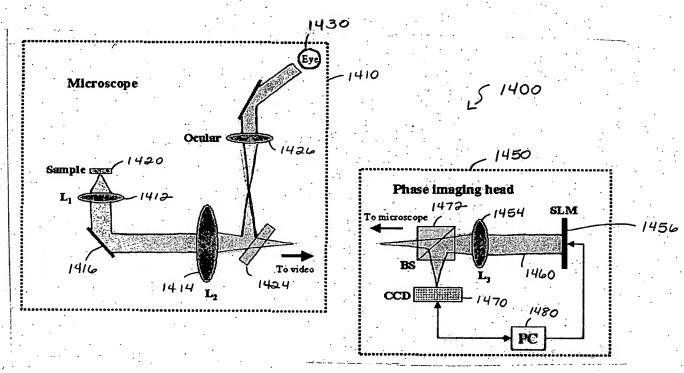
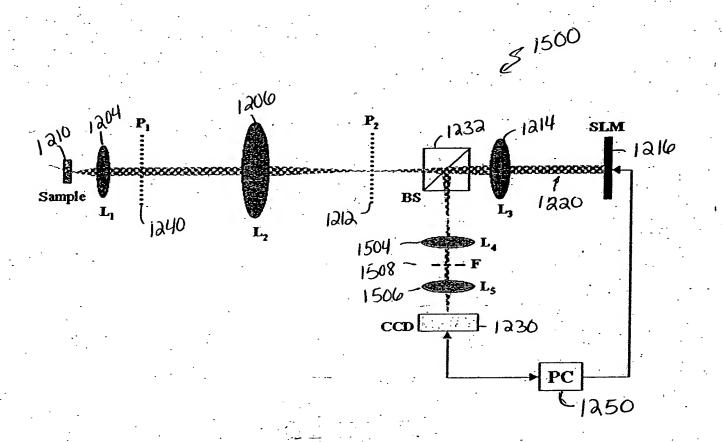
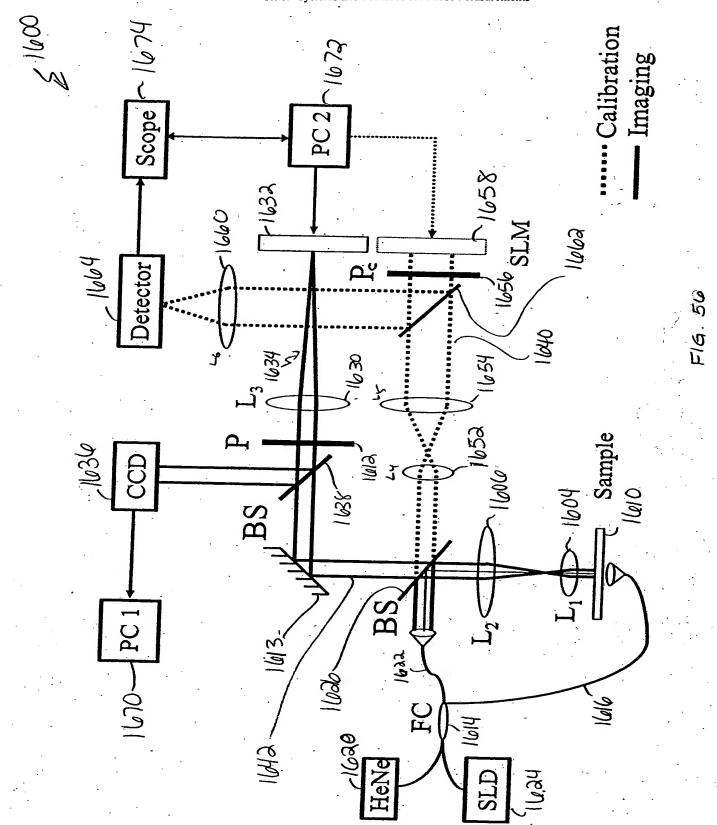
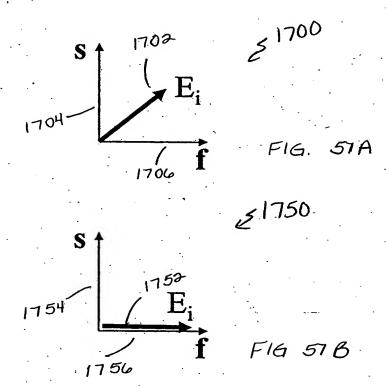


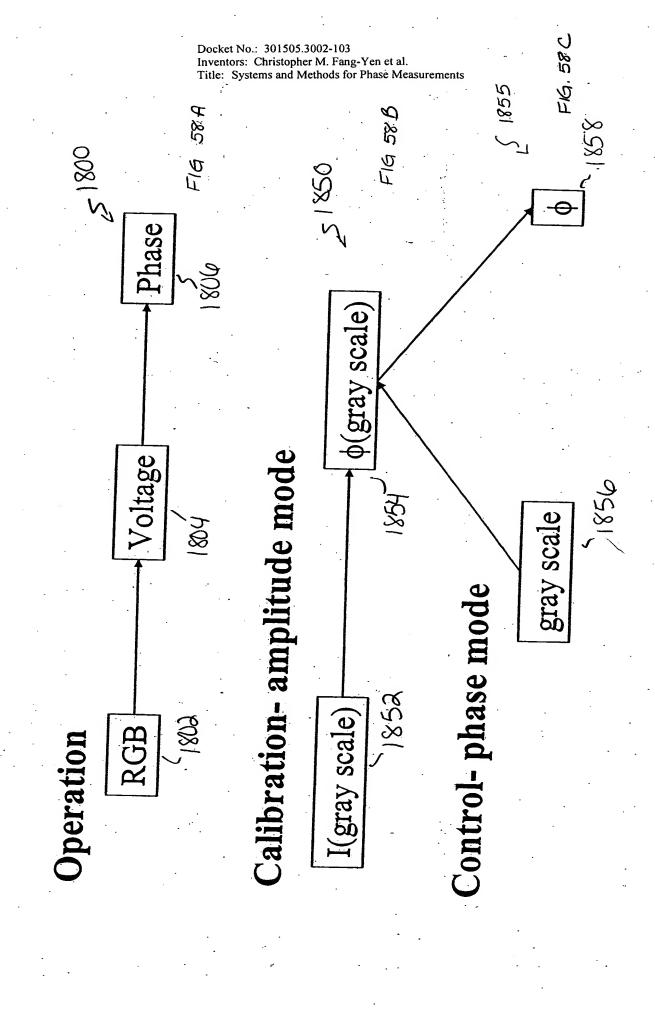
FIG. 54B

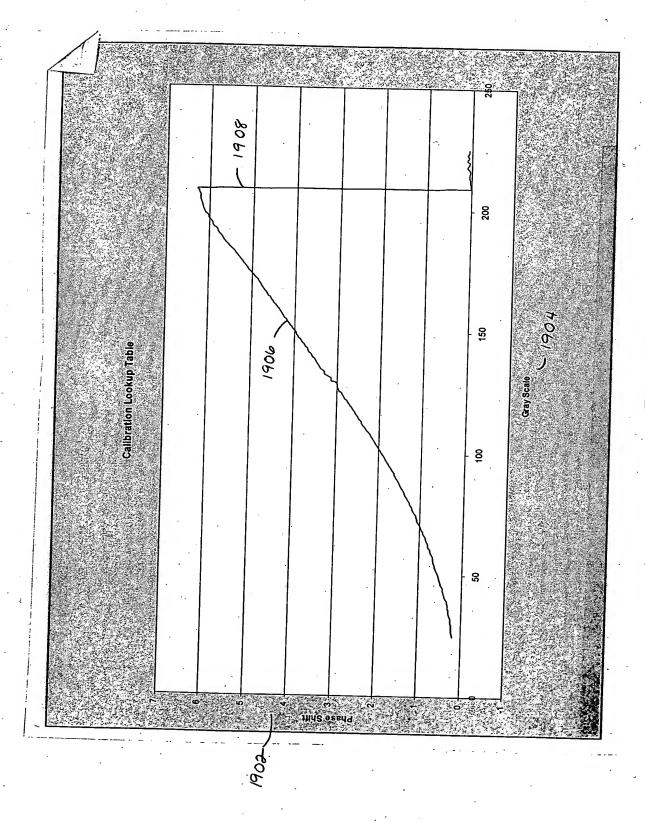


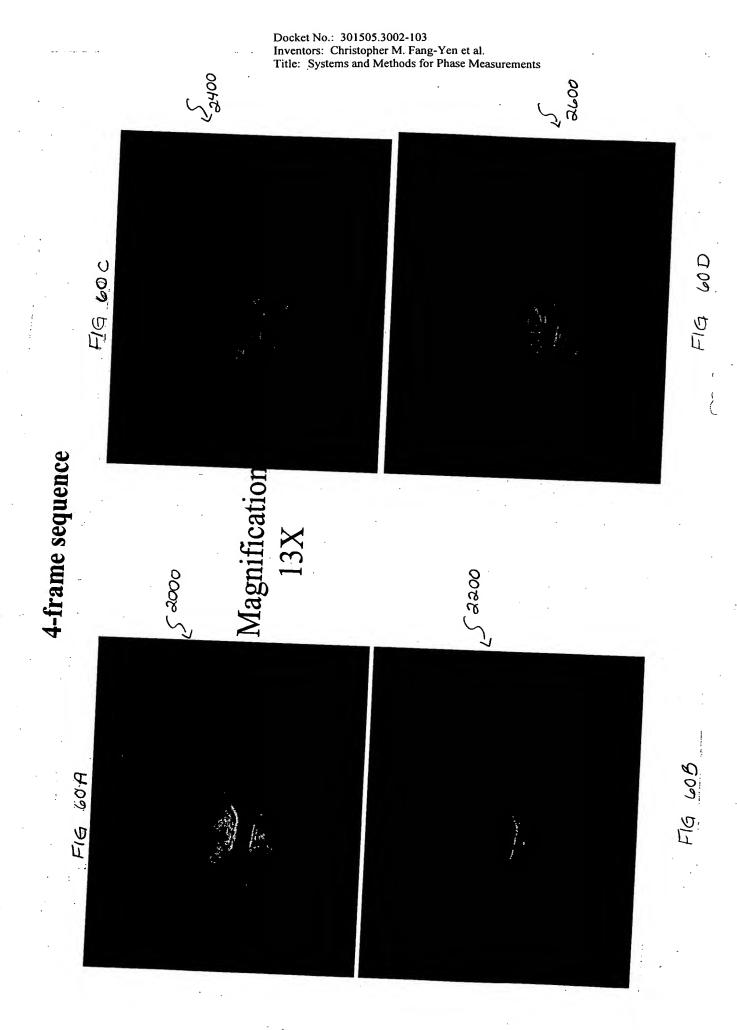
F16. 55

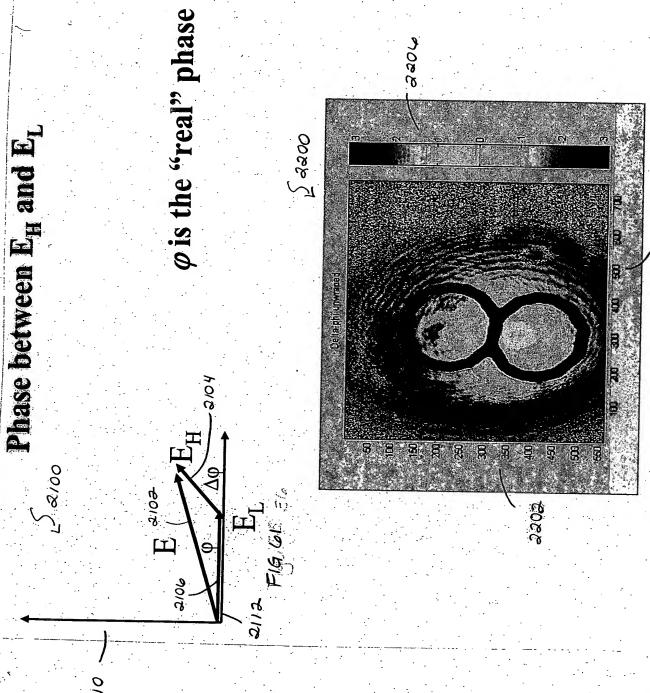




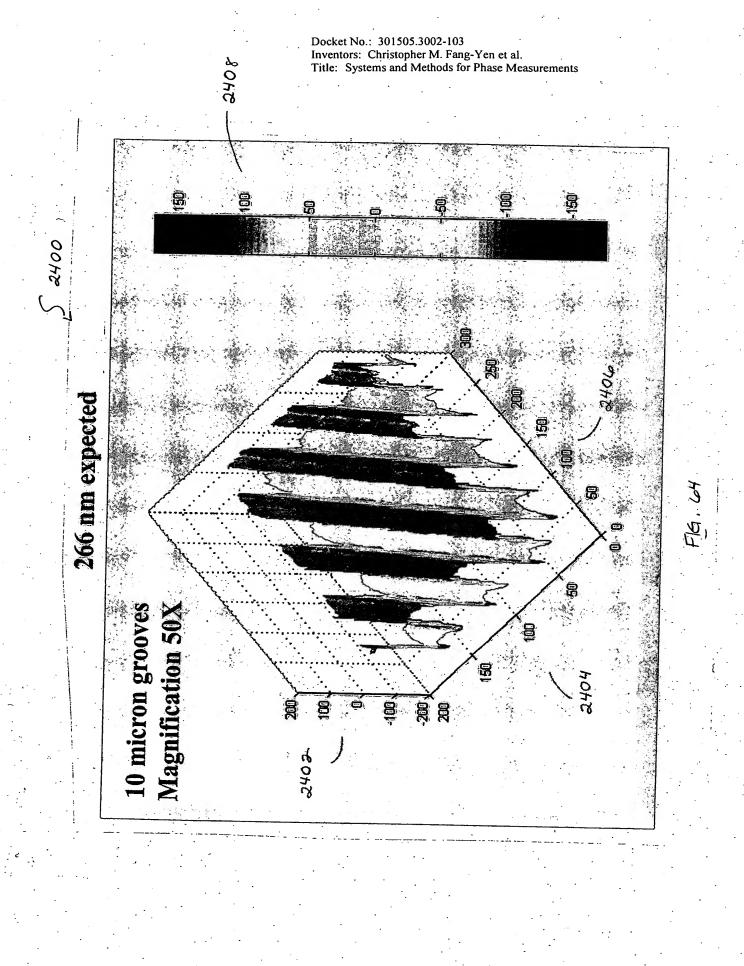


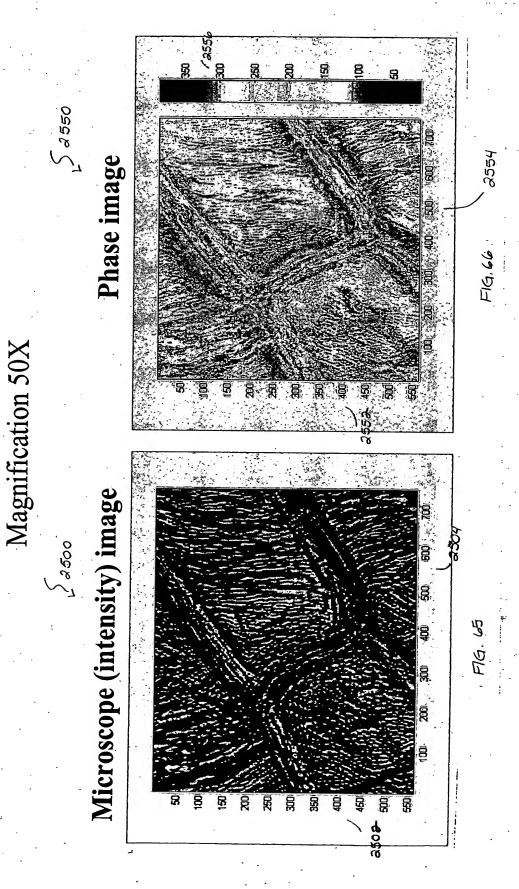


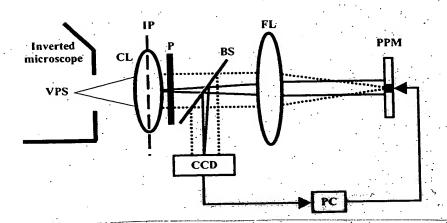




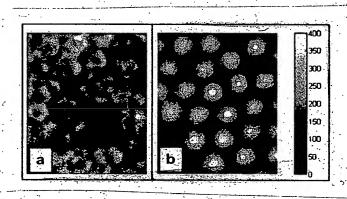
Phase image 140 nm expected







FIG



F16 68A

F16 L8B

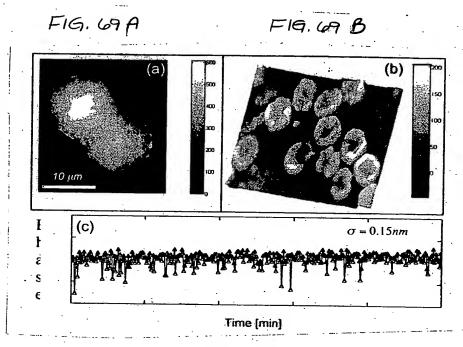


FIG. G.C